

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination DEMEOCQ, ETIENNE	
		Examiner	Art Unit	Page 1 of 1
		Gail Verbitsky	2859	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,068,400	05-2000	Nelson et al.	374/179
	B	US-6,210,036	04-2001	Eberle et al.	374/141
	C	US-5,070,732	12-1991	Duncan et al.	73/431
	D	US-3,650,154	03-1972	Arnett et al.	374/181
	E	US-5,088,835	02-1992	Shigezawa et al.	374/181
	F	US-6,074,089	06-2000	Hollander et al.	374/181
	G	US-RE30,735	09-1981	Ihlenfeldt et al.	374/181
	H	US-5,351,551	10-1994	Drubetsky et al.	73/755
	I	US-4,669,049	05-1987	Kosednar et al.	702/133
	J	US-5,735,605	04-1998	Blalock, Allen V.	374/179
	K	US-4,776,706	10-1988	Loiterman et al.	374/208
	L	US-4,863,283	09-1989	Falk, Richard A.	374/181
	M	US-4,718,777	01-1988	Mydynski et al.	374/181

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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